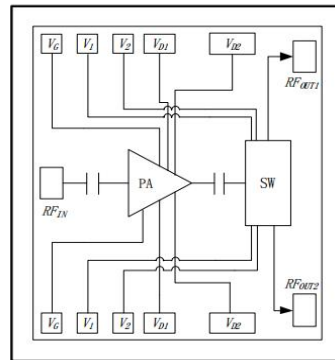


Performance

- Frequency: 5~7GHz
- Typical Signal Gain: 28dB
- Typical Pout: 46.5dBm@28V
- Typical PAE: 50%
- Typical Operating Current: 3.5A
- Bias: 28V, -2.0V (Typ.)
- Technology: 0.25um HEMT
- Mode: Pulse
- Size: 3.7*4.2mm*0.08mm

Function Diagram



Electrical Specifications

($T_A=25^\circ\text{C}$, $V_d=28\text{V}$, $V_g=-2.0\text{V}$, F: 5~7GHz, $P_{in}=25\text{dBm}$, $T=28\text{ms}$, $D=30\%$, Heat station temp. 70°C)

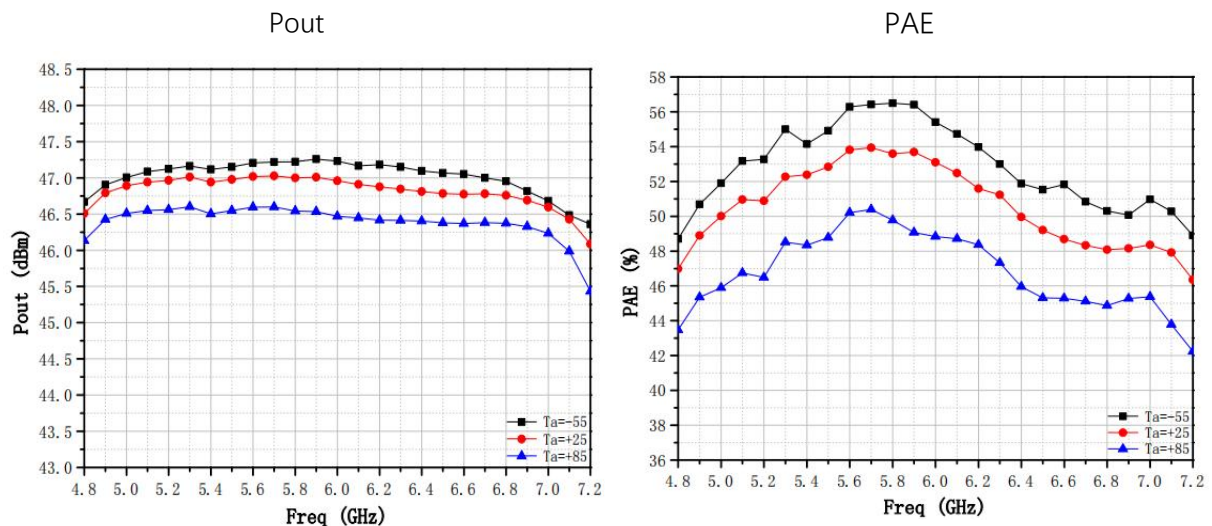
Symbol	Parameter	Min	Typical	Max	Unit
Pout	Saturated Power	-	46.5	-	dBm
Gp	Power Gain	-	21.5	-	dB
Id	Dynamic current	-	3.5	-	A
PAE	Power Added Efficiency	-	50	-	%

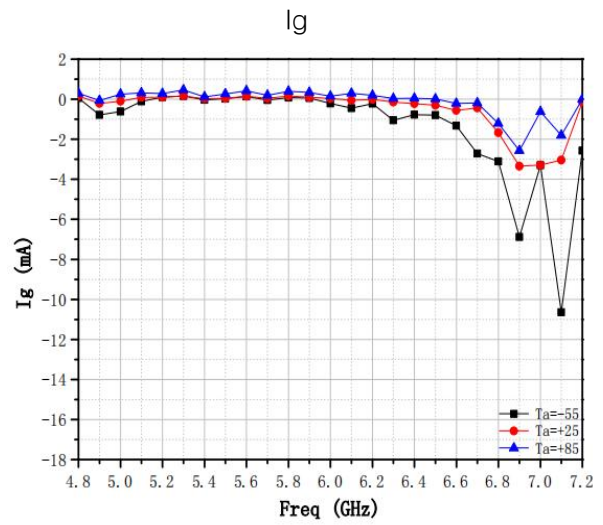
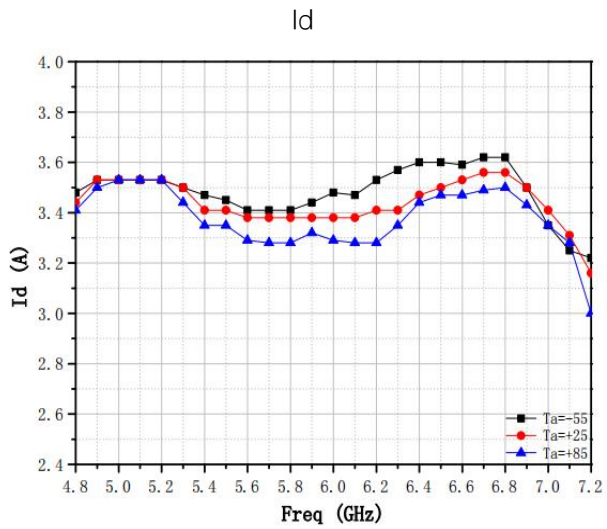
Electrical Specifications

($T_A=25^\circ\text{C}$, $V_d=28\text{V}$, $V_g=-2.0\text{V}$, F: 5~7GHz, $P_{in}=-15\text{dBm}$, Heat station temp. 70°C)

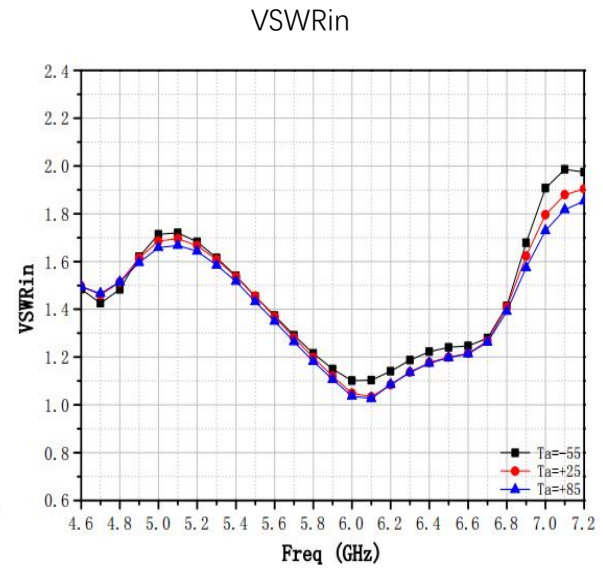
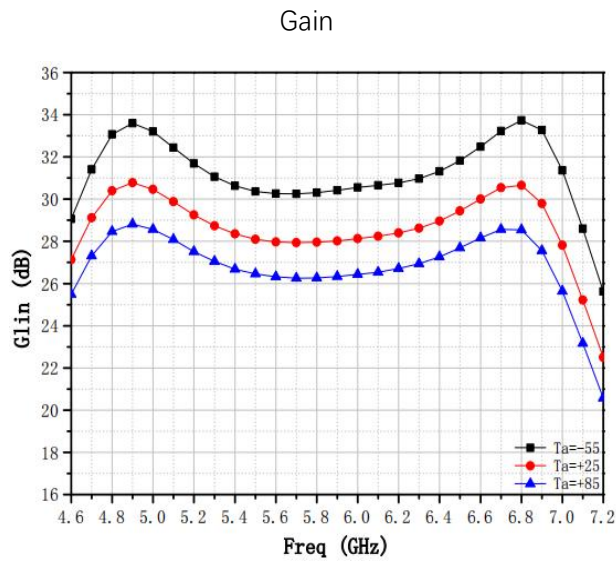
Symbol	Parameter	Min	Typical	Max	Unit
G	Small Signal Gain	-	28	-	dB
VSWRin	VSWRin	-	1.6	-	-
Idq	Static Current	-	2.7	-	A
Rth	Thermal Resistance	-	1.2	-	$^\circ\text{C}/\text{W}$

Big signal test curve @ different temperatures

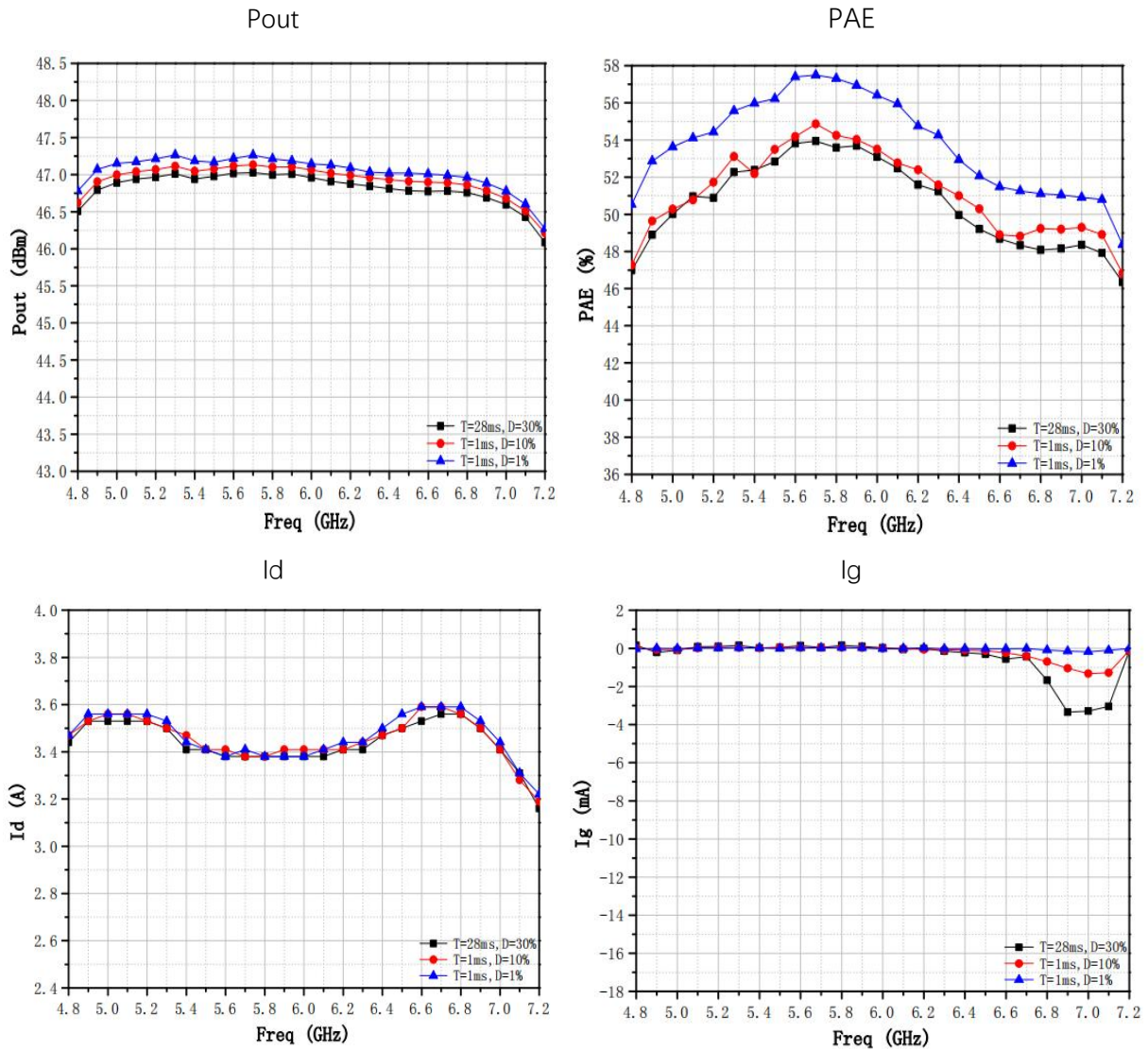




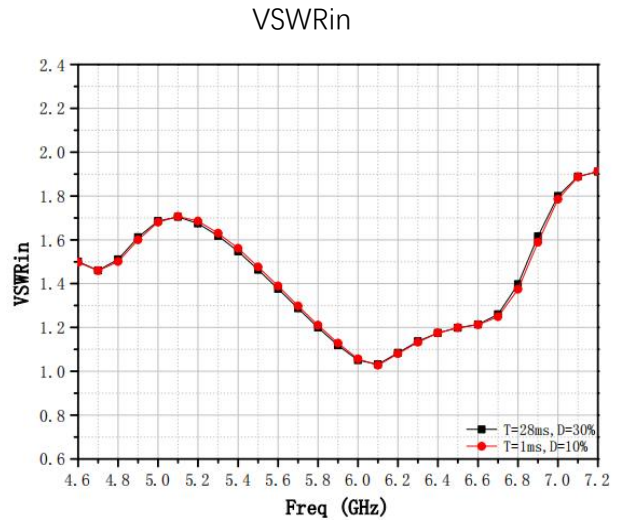
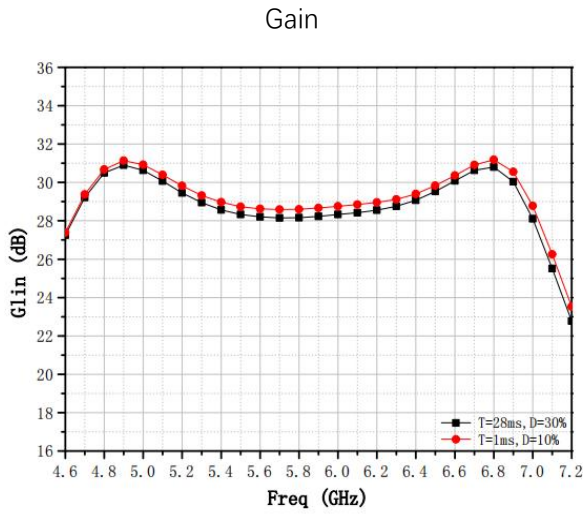
Small signal test curve @ different temperatures



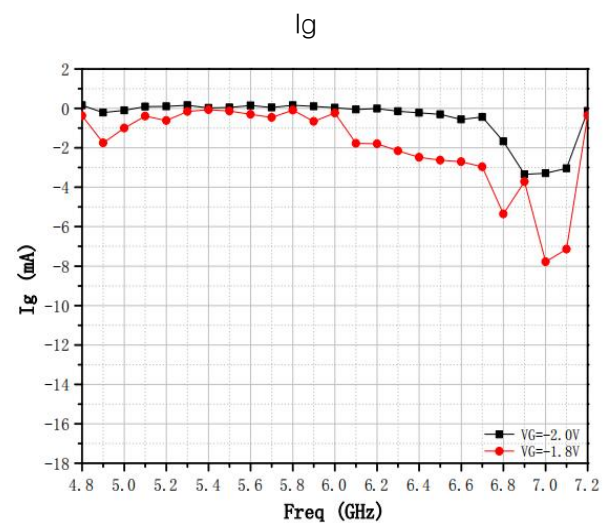
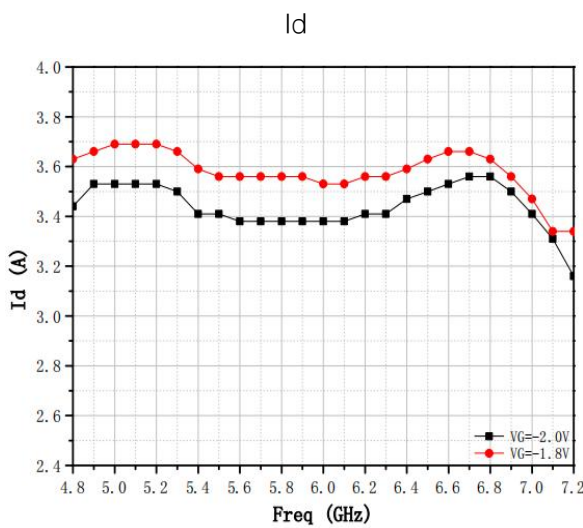
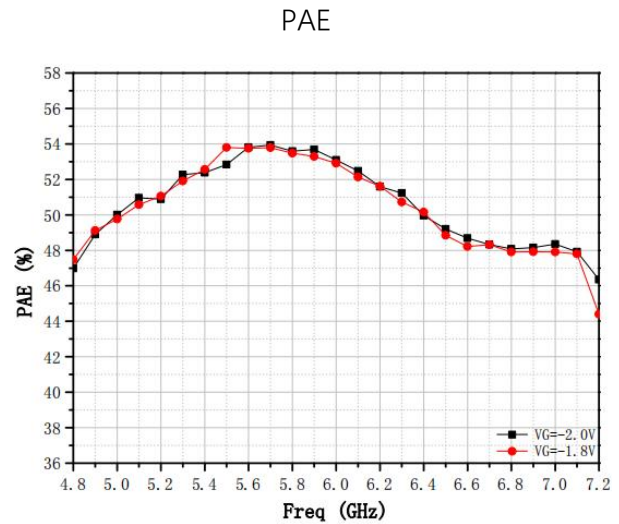
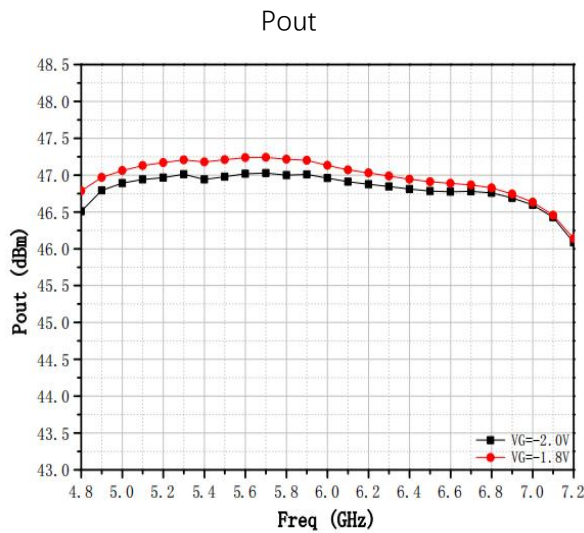
Big signal test curve @ different pulse conditions



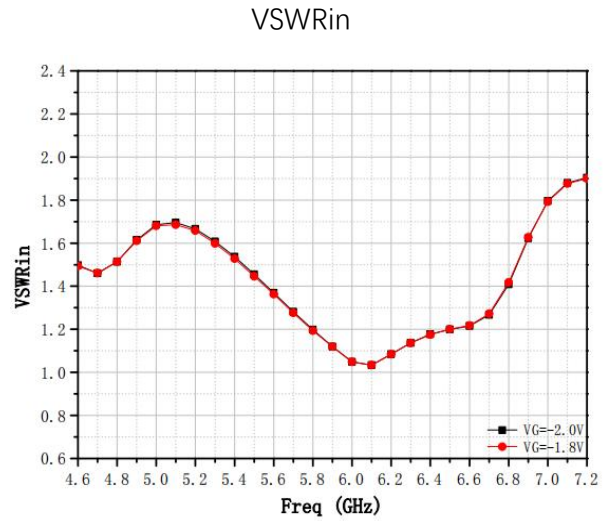
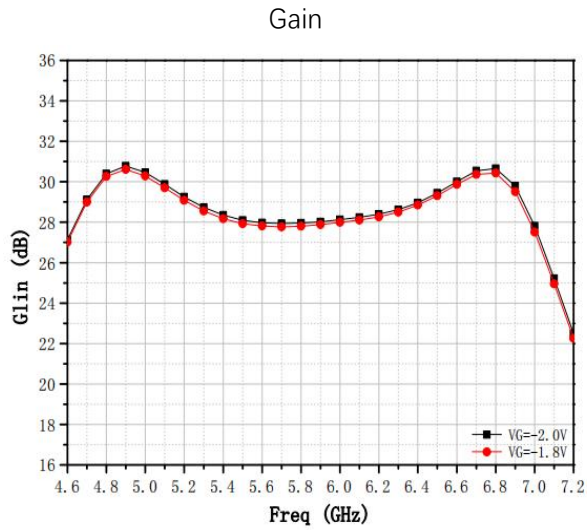
Small signal test curve @ different pulse conditions



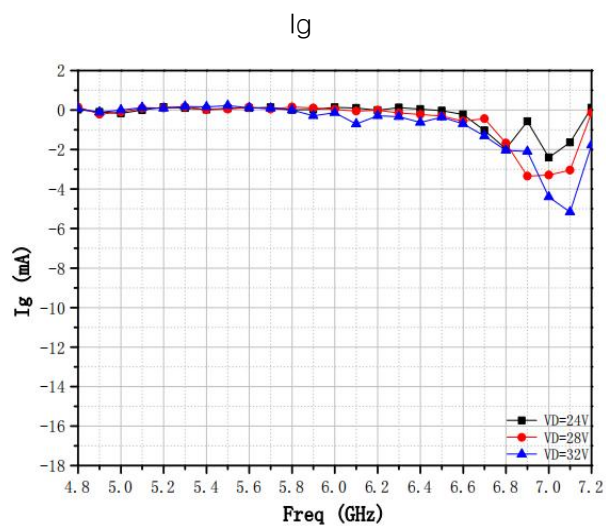
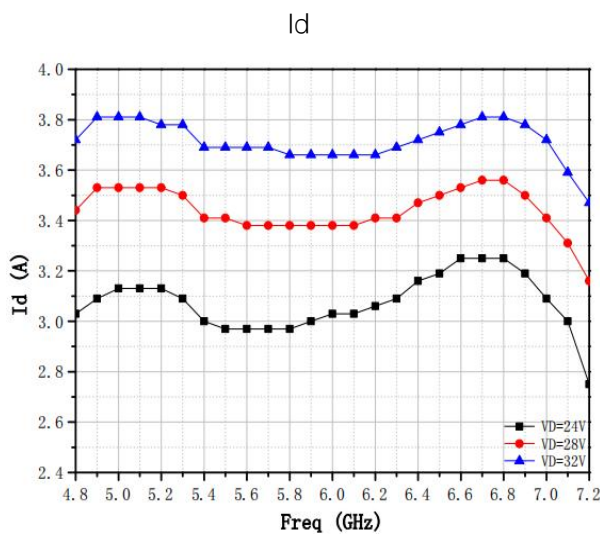
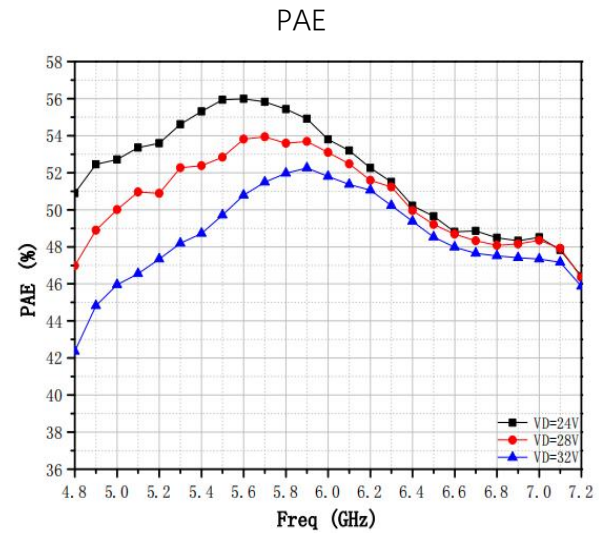
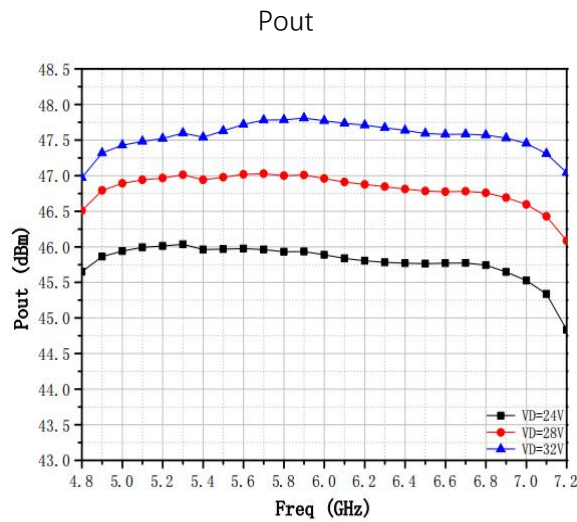
Big signal test curve @ different grid voltage conditions



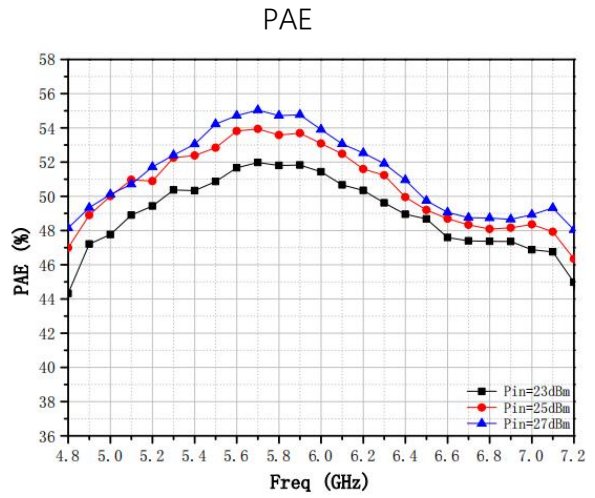
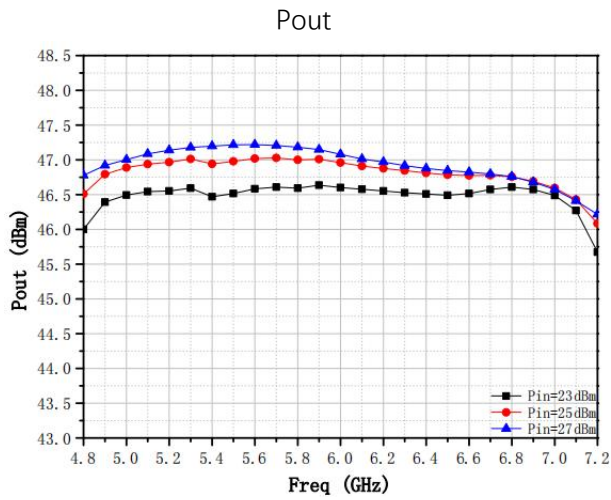
Small signal test curve @ different grid voltage conditions



Big signal test curve @ different drain voltage conditions



Big signal test curve @ different pin conditions



Absolute Max Ratings (TA=25°C)

Symbol	Parameter	Value	Remark
Vd	Drain Voltage	32V	
Vg	Grid Voltage	-10V	
Pd	DC Power	160W	
Pin	Input Power	31dBm	
Tch	Channel Temperature	225°C	1,2
Tm	Mounting Temperature	310°C	30 s, N2 Protection
Tstg	Storage Temperature	-65~150°C	

Exceeding any one or combination of these limits may cause permanent damage.